

Nanoscale electrical characterization of nanostructures and devices (Ramot)

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Lab Description

Nanoscale electrical characterization of nanostructures and devices, Kelvin probe force microscopy (KPFM), Nanowires and nanowire transistors, Solar Cells, Organic semiconductor devices and materials, Biological Field effect Transistors.

Available Research Services

We offer services for AFM and KPFM measurements-

Semiconductor and organic nano-structures characterization using ambient and ultra high vacuum (UHV) AFM and Kelvin Probe Force Microscopy (KPFM), low temperature (LT) UHV KPFM, SEM.

Time-resolved and steady-state photoluminescence in the range 400-1400 nm and at a temperature range 25-800 K

Lab facilities

1. AFM and KPFM measurements
2. Time-resolved temperature dependent photoluminescence measurements

Contact Information

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